

<b>Notice of References Cited</b>	Application/Control No. 10/623,570	Applicant(s)/Patent Under Reexamination KIM, JUNG-HOON	
	Examiner Hai L. Nguyen	Art Unit 2816	Page 1 of 1

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*	B	US-5,642,069	06-1997	Waite, John C.	327/292
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**NON-PATENT DOCUMENTS**

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